

STP9NK90ZFP-VB Datasheet

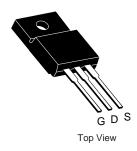
N-Channel 900 V (D-S) Super Junction Power MOSFET

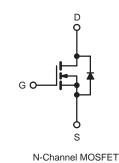
PRODUCT SUMMARY					
V _{DS} (V)	900				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	0.95			
Q _g (Max.) (nC)	200				
Q _{gs} (nC)	24				
Q _{gd} (nC)	110				
Configuration	Single				

TO-220 FULLPAK

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted) PARAMETER SYMBOL LIMIT UNIT Drain-Source Voltage V_{DS} 900 V Gate-Source Voltage ± 20 V_{GS} T_C = 25 °C 7.0 V_{GS} at 10 V Continuous Drain Current I_D T_C = 100 °C А 5.5 Pulsed Drain Currenta 21 I_{DM} W/°C Linear Derating Factor 1.5 770 Single Pulse Avalanche Energy^b E_{AS} mJ Repetitive Avalanche Current^a 7.8 А I_{AR} Repetitive Avalanche Energy^a 19 mJ E_{AR} T_C = 25 °C Maximum Power Dissipation 65 W P_{D} Peak Diode Recovery dV/dtc 2.0 dV/dt V/ns Operating Junction and Storage Temperature Range T_J, T_{stg} - 55 to + 150 °C Soldering Recommendations (Peak Temperature) for 10 s 300d 10 lbf · in Mounting Torque 6-32 or M3 screw 1.1 N·m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/µs, V_{DD} \leq 600 V, T_J \leq 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply



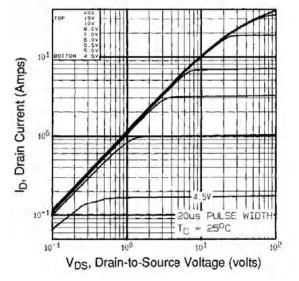
semi www.VBsemi.com

THERMAL RESISTANCE RATI	NGS								
PARAMETER	SYMBOL	TYP.		MAX.		UNIT			
Maximum Junction-to-Ambient	R _{thJA}	-		40					
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24				°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.65							
		. N							
SPECIFICATIONS ($T_J = 25 \text{ °C}, u$		1			-	r	1	ł	
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT	
Static		1				1	1	1	
Drain-Source Breakdown Voltage	V _{DS}		= 0 V, I _D = 2	-	900	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$		e to 25 °C,		-	0.98	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}		= V_{GS} , I_D =		2.0	-	4.0	V	
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20 V$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =	= 900 V, V _G	_{is} = 0 V	-	-	100	μA	
	-255	-		/, T _J = 125 °C	-	-	500	μ.,	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	۱ _D	₀ = 5.6 A ^b		0.95	-	Ω	
Forward Transconductance	g fs	$V_{DS} =$	= 100 V, I _D =	= 5.6 A ^b	5.6	-	-	S	
Dynamic									
Input Capacitance	C _{iss}		V _{GS} = 0 V	,	-	3100	-		
Output Capacitance	C _{oss}	V _{DS} = 25 V,		-	800	-	pF		
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, se	e fig. 5	-	490	-		
Total Gate Charge	Qg				-	-	200	nC	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		A, V _{DS} = 400 V, ig. 6 and 13 ^b	-	-	24		
Gate-Drain Charge	Q _{gd}		0001		-	-	110		
Turn-On Delay Time	t _{d(on)}				-	19	-		
Rise Time	t _r	V _{DD} = 400 V, I _D = 5.6 A,		-	38	-	1		
Turn-Off Delay Time	t _{d(off)}	R _g =	= 6.2 Ω, R _D = see fig. 10	= 52 Ω ^{1b}	-	120	-	ns	
Fall Time	t _f	see lig. 10 ²		-	39	-	1		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH		
Internal Source Inductance	L _S			-	13	-			
Drain-Source Body Diode Characteristic	s	·							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	A		
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21			
Body Diode Voltage	V _{SD}	$T_J = 25 \text{ °C}, I_S = 5.6 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.8	V		
Body Diode Reverse Recovery Time	t _{rr}	T.=	25 °C, I _F =	5.6 A.	-	650	980	ns	
Body Diode Reverse Recovery Charge	Q _{rr}		/dt = 100 A		-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time	is nealiaible (turn	-on is do	n is dominated by L_S and L_D)			

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



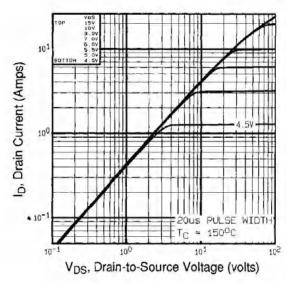


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

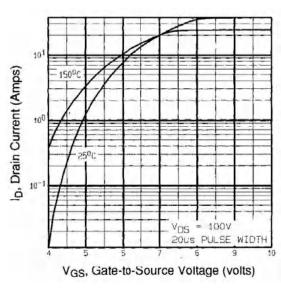
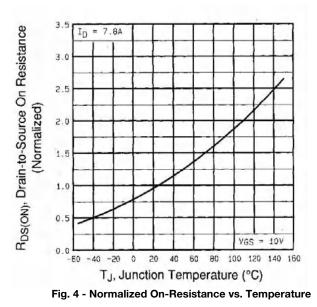


Fig. 3 - Typical Transfer Characteristics





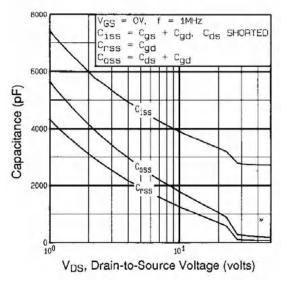


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

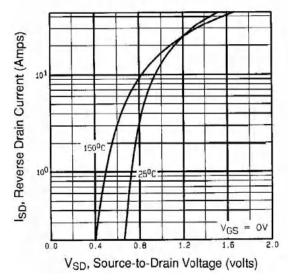


Fig. 7 - Typical Source-Drain Diode Forward Voltage

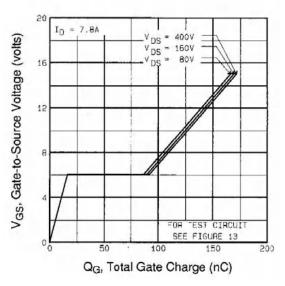
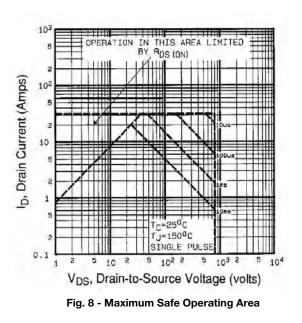


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





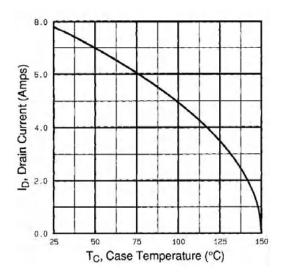


Fig. 9 - Maximum Drain Current vs. Case Temperature

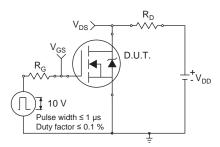


Fig. 10a - Switching Time Test Circuit

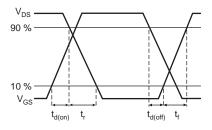


Fig. 10b - Switching Time Waveforms

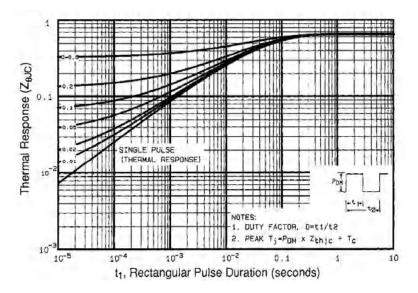


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



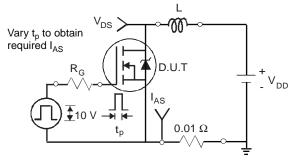


Fig. 12a - Unclamped Inductive Test Circuit

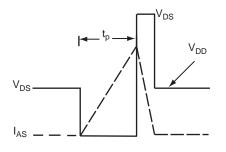


Fig. 12b - Unclamped Inductive Waveforms

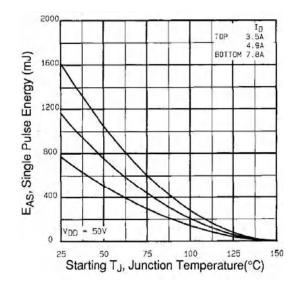


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

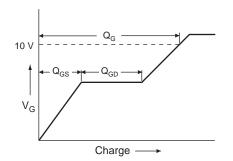


Fig. 13a - Basic Gate Charge Waveform

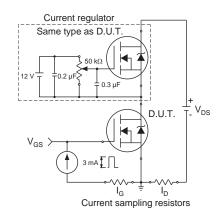
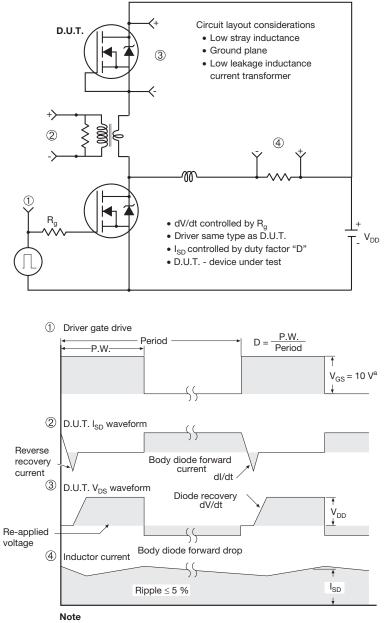


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

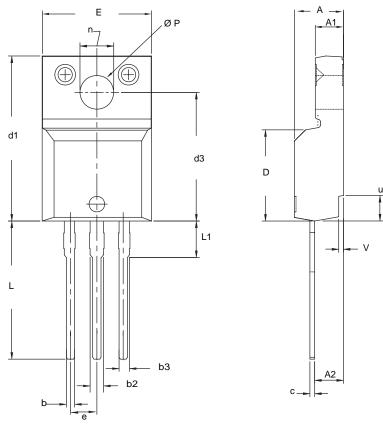


a. $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



DIM.	MILLI	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
А	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
C	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54 BSC		0.100 BSC		
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
ØP	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness.

5. No chipping or package damage.



Disclaimer

All products due to improve reliability, function or design or for other reasons, product specifications and data are subject to change without notice.

Taiwan VBsemi Electronics Co., Ltd., branches, agents, employees, and all persons acting on its or their representatives (collectively, the "Taiwan VBsemi"), assumes no responsibility for any errors, inaccuracies or incomplete data contained in the table or any other any disclosure of any information related to the product.(www.VBsemi.com)

Taiwan VBsemi makes no guarantee, representation or warranty on the product for any particular purpose of any goods or continuous production. To the maximum extent permitted by applicable law on Taiwan VBsemi relinquished: (1) any application and all liability arising out of or use of any products; (2) any and all liability, including but not limited to special, consequential damages or incidental; (3) any and all implied warranties, including a particular purpose, non-infringement and merchantability guarantee.

Statement on certain types of applications are based on knowledge of the product is often used in a typical application of the general product VBsemi Taiwan demand that the Taiwan VBsemi of. Statement on whether the product is suitable for a particular application is non-binding. It is the customer's responsibility to verify specific product features in the products described in the specification is appropriate for use in a particular application. Parameter data sheets and technical specifications can be provided may vary depending on the application and performance over time. All operating parameters, including typical parameters must be made by customer's technical experts validated for each customer application. Product specifications do not expand or modify Taiwan VBsemi purchasing terms and conditions, including but not limited to warranty herein.

Unless expressly stated in writing, Taiwan VBsemi products are not intended for use in medical, life saving, or life sustaining applications or any other application. Wherein VBsemi product failure could lead to personal injury or death, use or sale of products used in Taiwan VBsemi such applications using client did not express their own risk. Contact your authorized Taiwan VBsemi people who are related to product design applications and other terms and conditions in writing.

The information provided in this document and the company's products without a license, express or implied, by estoppel or otherwise, to any intellectual property rights granted to the VBsemi act or document. Product names and trademarks referred to herein are trademarks of their respective representatives will be all.

Material Category Policy

Taiwan VBsemi Electronics Co., Ltd., hereby certify that all of the products are determined to be RoHS compliant and meets the definition of restrictions under Directive of the European Parliament 2011/65 / EU, 2011 Nian. 6. 8 Ri Yue restrict the use of certain hazardous substances in electrical and electronic equipment (EEE) - modification, unless otherwise specified as inconsistent.(www.VBsemi.com)

Please note that some documents may still refer to Taiwan VBsemi RoHS Directive 2002/95 / EC. We confirm that all products identified as consistent with the Directive 2002/95 / EC European Directive 2011/65 /.

Taiwan VBsemi Electronics Co., Ltd. hereby certify that all of its products comply identified as halogen-free halogen-free standards required by the JEDEC JS709A. Please note that some Taiwanese VBsemi documents still refer to the definition of IEC 61249-2-21, and we are sure that all products conform to confirm compliance with IEC 61249-2-21 standard level JS709A.